

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 11-295560
(43)Date of publication of application : 29.10.1999

(51)Int.Cl.

G02B 6/42
H01L 31/12
H01S 3/18
H04B 10/08

(21)Application number : 10-097512
(22)Date of filing : 09.04.1998

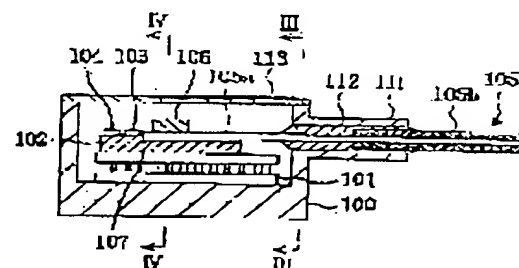
(71)Applicant : MATSUSHITA ELECTRIC IND CO LTD
(72)Inventor : NISHIKAWA TORU
MITSUTA MASAHIRO
UNO TOMOAKI
MATSUDA KENICHI

(54) MODULE FOR OPTICAL COMMUNICATION AND INSPECTION METHOD THEREFOR

(57)Abstract:

PROBLEM TO BE SOLVED: To control the temperature of a semiconductor laser element from the outside of a package, to lower the price of a module for optical communication and to miniaturize it.

SOLUTION: A Peltier element 101 is provided on the bottom part of the package 100 and a base 102 is fixed on the Peltier element 101. On the base 102, the semiconductor laser element 103 and a photodetector 104 for monitoring are fixed. A recessed groove whose cross section is chevron-shaped is formed on the upper surface of the base 102 so as to be extended in an optical axis direction and the incident part 105a of an optical fiber 105 is fitted to the recessed groove. A fiber pressing member 106 provided with the recessed groove whose cross section is trapezoidal is fixed on the upper side of the base 102 and the incident part 105a of the optical fiber 105 is clamped by the base 102 and the fiber pressing member 106. A notched part 107 extended in a direction perpendicular to an optical axis is formed at the base 102 and the left end face of the optical fiber 105 is abutted on the wall surface on the side of the semiconductor laser element 103 of the notched part 107.



LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]

Copyright (C): 1998.2003 Japan Patent Office

Best Available Copy